

IGBT Chip in NPT-technology

FEATURES:

- 1200V NPT technology
- 180µm chip
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

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Applications:

• drives, SMPS, resonant applications

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC25T120CS	1200V	15A	5.71 x 4.53 mm ²	sawn on foil	Q67050-A4114

MECHANICAL PARAMETER:

Raster size	5.71 x 4.53	mm ²			
Emitter pad size	2 x (2.18 x 1.6)]			
Gate pad size	1.09 x 0.68]			
Area total / active	25.9 / 18.7]			
Thickness	180	μm			
Wafer size	150	mm			
Flat position	270	grd			
Max.possible chips per wafer	555 pcs				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	Al, <500μm				
Reject Ink Dot Size	Ø 0.65mm; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _j =25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	Α
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	45	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_i =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions		Value		
Turumeter	Cymbol .	Conditions	min.	typ.	max.	Unit
Collector-emitter breakdown voltage	V _{(BR)CES}	V _{GE} =0V , I _C =1mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =15A	2.5	3.0	3.6	V
Gate-emitter threshold voltage	V _{GE(th)}	I_C =0.6mA , V_{GE} = V_{CE}	3.0	4.0	5.0	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			2	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			480	nA

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
r ai ailietei	Symbol	Conditions	min.	typ.	max.]
Input capacitance	Ciss	V _{CE} =25V,	-	1250		pF
Output capacitance	Coss	$V_{GE}=0V$,	-	100		
Reverse transfer capacitance	Crss	f=1MHz	-	65		

SWITCHING CHARACTERISTICS (tested at component), Inductive Load

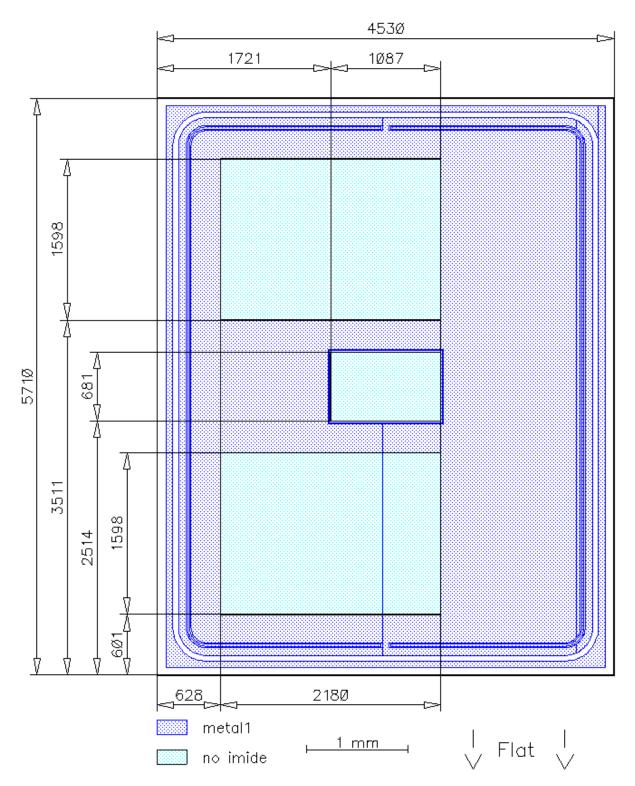
Parameter	Symbol	Conditions 1)	Value			Unit
	Symbol	Conditions	min.	typ.	max.	Onne
Turn-on delay time	$t_{d(on)}$	T _j =150°C	-	38		ns
Rise time	t_{r}	$V_{\rm CC} = 800 \text{V},$	-	30		
Turn-off delay time	$t_{d(off)}$	I _C =15A, V _{GE} =-15/15V,	-	652		
Fall time	t_{f}	$R_{\rm G}$ = 33 Ω	-	31		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:

Die-Size 4530 um x 5710 um





FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet	SGP15N120				
DESCRIPTION:					
AQL 0,65 for visual inspection according to failure catalog					
Electrostatic Discharge Sensitive Device according to MIL-STD 883					
Test-Normen Villach/Prüffeld					

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